

21st International Workshop on DEPFET Detectors and Applications

Monday, 29 May 2017

Module Testing (16:00 - 18:00)

-Conveners: Christian Koffmane

time	[id] title	presenter
16:00	[73] Gated Mode - System Aspects	Mr MUELLER, Felix
16:25	[74] Probe Card Testing	GOMIS, Pablo
16:40	[75] Interplay of EPICS, BonnDAQ, python scripts, DHE and JTAG	PASCHEN, Botho
17:00	[76] Automation of mass testing (coding guidelines, etc. and Slow Control)	Mr SCHREECK, Harrison Mr WIEDUWILT, Philipp
17:25	[77] Mass Testing	LEITL, Philipp
17:45	[78] Characterization of the Belle II final chipset and matrix on Hybrid 5	LEIBROCK, Barbara